

Contents

Part I Spectroscopic SPM at the Resolution Limits

- 1 Excitation and Mechanisms of Single Molecule Reactions
in Scanning Tunneling Microscopy 3
Peter Maksymovych
- 2 High-Resolution Architecture and Structural Dynamics
of Microbial and Cellular Systems: Insights from in Vitro
Atomic Force Microscopy 39
Alexander J. Malkin and Marco Plomp

Part II Dynamic Spectroscopic SPM

- 3 Dynamic Force Microscopy and Spectroscopy
in Ambient Conditions: Theory and Applications 71
Hendrik Hölscher, Jan-Erik Schmutz, and Udo D. Schwarz
- 4 Measuring Mechanical Properties on the Nanoscale
with Contact Resonance Force Microscopy Methods 95
D.C. Hurley
- 5 Multi-Frequency Atomic Force Microscopy 125
Roger Proksch
- 6 Dynamic Nanomechanical Characterization
Using Multiple-Frequency Method 153
Ozgar Sahin

Part III Thermal Characterization by SPM

- 7 Toward Nanoscale Chemical Imaging: The Intersection
of Scanning Probe Microscopy and Mass Spectrometry 181
Olga S. Ovchinnikova

- 8 Dynamic SPM Methods for Local Analysis of Thermo-Mechanical Properties.....** 199
M.P. Nikiforov and R. Proksch

Part IV Electrical and Electromechanical SPM

- 9 Advancing Characterization of Materials with Atomic Force Microscopy-Based Electric Techniques.....** 233
Sergei Magonov, John Alexander, and Shijie Wu
- 10 Quantitative Piezoresponse Force Microscopy: Calibrated Experiments, Analytical Theory and Finite Element Modeling.....** 301
Lili Tian, Vasudeva Rao Aravind, and Venkatraman Gopalan
- 11 High-Speed Piezo Force Microscopy: Novel Observations of Ferroelectric Domain Poling, Nucleation, and Growth** 329
Bryan D. Huey and Ramesh Nath
- 12 Polar Structures in Relaxors by Piezoresponse Force Microscopy** 345
V.V. Shvartsman, W. Kleemann, D.A. Kiselev,
I.K. Bdikin, and A.L. Khoklin
- 13 Symmetries in Piezoresponse Force Microscopy.....** 385
Andreas Ruediger

Part V Novel SPM Concepts

- 14 New Capabilities at the Interface of X-Rays and Scanning Tunneling Microscopy** 405
Volker Rose, John W. Freeland, and Stephen K. Streiffer
- 15 Scanning Ion Conductance Microscopy.....** 433
Johannes Rheinlaender and Tilman E. Schäffer
- 16 Combined Voltage-Clamp and Atomic Force Microscope for the Study of Membrane Electromechanics.....** 461
Arthur Beyder and Frederick Sachs
- 17 Dynamic and Spectroscopic Modes and Multivariate Data Analysis in Piezoresponse Force Microscopy** 491
B.J. Rodriguez, S. Jesse, K. Seal, N. Balke, S.V. Kalinin, and R. Proksch

Contents

xiii

18 Polarization Behavior in Thin Film Ferroelectric Capacitors at the Nanoscale.....	529
A. Gruverman	
Index.....	541